S	earcl	h Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/810,320	STOCK ET AL.	
Examiner	Art Unit	
Anthony Weier	1761	

	SEARCHED		
Class	Subclass	Date	Examiner
426	614, 601	6/6/2007	AW
)			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAF	NOTES ICH STRATEGY	<b>'</b> )
	DATE	EXMR
Inventor Search	6/6/2007	AW
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